

LEHIGHTON ELECTRONICS INC.

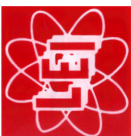
LEHIGHTON ELECTRONICS, INC.

Quality Service Since 1963
P.O. Box 328
208 Memorial Dr.
Lehigh, PA 18235-0328

CALL/CONTACT

Phone: (800) 535-1112
Fax: (610) 377-6820
E-mail: salesinfo@lehighton.com
Website: www.lehighton.com

MODEL 2017



REV002

LEI MERCURY PROBES



Model 2017B

SYSTEM FEATURES:

- Permanent machined orifice plate (no Mylar replacement)
- Multiple Schottky available on a single orifice plate
- Minimal series resistance via innovative Schottky/return dot configuration
- Precision vacuum control.
- Mercury is supplied to the sample only when vacuum is applied
- Unique vacuum Hg-pull/sample hold-down configuration improves repeatability of the mercury Schottky

STANDARD MODEL FEATURES:

- **Model 2017:** For use with conductive substrates. Equipped with dot sizes of 0.64 mm (.025"), 1.27 mm, (.050"), 1.91 mm (.075") and 2.29 mm (.090") diameter; return contact formed by backside metal disk.
- **Model 2017B:** For use with Semi-insulating as well as conductive substrates. Equipped with dot sizes of 0.46 mm (.018") and 0.64mm, (.025"), with 3.81mm (0.150") mercury return contact or return contact formed by backside disk.
- Test sample size from 6.4 mm x 6.4 mm (.25"x.25") to 150 mm (6") wafers standard models)
- *Additional dot sizes and custom designs available*

Nondestructive Measurement of Semiconductor Wafers